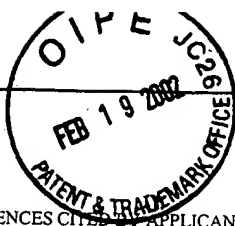


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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	US 5,650,375 (equivalent of EP 0713646)	7/22/97	Hacker et al			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AD	JP 10-287503	10/27/98	Japan				
	AE	JP 10-279406	10/20/98	Japan				
	AF	WO 98/33383	8/6/98	PCT				
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	AN	Chemical Abstracts, Vol. 101, No. 19, 1984, S. Varkonda et al, also referred to as XP002176644
	AO	Varkonda et al, Vol. 24, No. 6, 1984, pp. 177-179.
	AP	Chemical Abstracts, Vol. 130, No. 2, 1998, Nabeya et al, also referred to as XP 002176645.
	AQ	Database WPI, also referred to as XP 002176646.

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<i>Sen</i>	AA	5,428,000	06/27/95	Innami, et al.	504	104	
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	AD						
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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